



SCIENTIFIC EXCELLENCE ON STAGE

The SCIENTIFIC VISION DAYS are the well-established lecture series of the AIT Austrian Institute of Technology and its partners. Experts from science and industry will present cutting-edge technologies covering all aspects of machine vision.

This year's topics include

- Industrial Inspection
- Deep Learning
- Inline Computational Imaging
- 3D Vision

Kontakt

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SCIENTIFIC VISION DAYS 2022

SCIENTIFIC EXCELLENCE ON STAGE at Booth **8C50**

Tuesday 04.10.2022

Wednesday 05.10.2022

10:00 **Inspecting Soft Biological Materials Using X-Rays for 3D Insight**
 Philipp Schneider
 AIT & University of Southampton

10:00 **Point Light Modeling for the Photometric Stereo Problem**
 Roberto Mecca
 Toshiba Europe

10:20 **Fast and High-Resolution UV Imaging with SVS-Vistek's New Camera fxo487**
 Yvan Eilers
 SVS Vistek

10:20 **MotionCam-3D Color | The Technological Silver Bullet for Modern Machine Vision Challenges**
 Svorad Stolz
 Photoneo

10:40 **Event-Based Vision | Fiducial Marker Tracking**
 Adam Loch
 AIT & TU Wien

10:40 **Measurement Accuracy in High-Speed 3D Inline Microscopy**
 Lukas Traxler
 AIT

11:00 **Integration of Spectroscopic Inspection for In-Line Quality Control**
 Victor Izquierdo
 IREC-CERCA

11:00 **Miniaturized Scanning and 3D Modelling Systems**
 Manfred Gruber
 AIT

11:20 **High-Speed Imaging and Processing at the Edge**
 Max Scholz
 Mikrotron

11:20 **An Exposition of Pioneering Optical Advancements for Inline Computational Imaging**
 Doris Antensteiner
 AIT

11:40 **On the Significant Benefits of Release 4 of the EMVA Standard 1288 for Modern Camera Characterization**
 Bernd Jähne
 EMVA

11:40 **GPU-Based Digital Image Correlation System for Real-Time Material Testing Applications**
 Andreas Blug
 Fraunhofer IPM

Lunch break

Lunch break

13:00 **AI without Labelers**
 Luigi Di Stefano
 University of Bologna

13:00 **Transfer Learning for Automated Quality Inspection**
 Florian Kromp
 SCCH

13:20 **Responsible Introduction of AI in Industrial Inspection Processes**
 Christian Kapeller
 AIT

13:20 **VISAGE | A TinyML ASIC Allowing Solar-Powered Face Analysis at the Edge**
 Petar Jokic
 CSEM

13:40 **AI vs. Classical Machine Vision**
 Alkhazur Manakov
 Imago Technologies

13:40 **Responsible Introduction of AI in Industrial Inspection Processes**
 Christian Kapeller
 AIT

14:00 **RISPECT | Quality Inspection of Translucent Micro-Structured Functional Surfaces**
 Lukas Traxler
 AIT

14:00 **Quantification of Second Phase Particles in Metals Using Deep Learning | Segmentation of Nanoscale Dispersoids in Aluminum Alloys**
 Aurel Arnoldt
 LKR

14:20 **Smart 3D Surface Inspection with xposure:photometry**
 Ernst Bodenstorfer
 AIT

14:20 **AI-Assisted Spatial Vision**
 Norbert Hainitz
 AIT

14:40 **3D Visualization and Analysis for Additive Manufacturing**
 Harald Steinlechner
 Aardworx

14:40 **AI-Supported and Model-Based Augmented Reality in Industrial Environments**
 Fabian Rucker
 Fraunhofer IGD

15:00 **flex:inspect | How to Deal with Deformations in Surface Inspection**
 Franz Daubner
 AIT

15:00 **Battery Foil Inspection with Inline-Photometry and AI**
 Philipp Schneider
 AIT

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